



Patent
Attorney's Docket No. 007413-056

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of)	
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Oliver KIENZLE et al.)	Group Art Unit: Unassigned
)	
Application No.: 10/614,825)	Examiner: Unassigned
)	
Filed: July 9, 2003)	Confirmation No.: 8138
)	
For: METHOD FOR THE ELECTRON-)	
MICROSCOPIC OBSERVATION OF A)	
SEMICONDUCTOR ARRANGEMENT)	
AND APPARATUS THEREFOR)	

FIRST
INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

In accordance with the duty of disclosure as set forth in 37 C.F.R. § 1.56, Applicants hereby submit the following information in conformance with 37 C.F.R. §§ 1.97 and 1.98.

The documents are being submitted within three (3) months of the filing or entry of the national stage of this application or before the first Office Action on the merits, whichever is later. Since documents are being filed within the time period set forth in 37 C.F.R. § 1.97(b) no fee or statement is required.

To assist the Examiner, the documents are listed on the attached form PTO-1449. It is respectfully requested that an Examiner-initialed copy of this form be returned to the undersigned.

DE 101 31 931 A1, listed on the attached PTO-1449 form, is a foreign language document. Both this document and U.S. Patent Publication No. 2003/0066961 A1 (also listed on the PTO-1449 form) reflect a claim for foreign priority to German Patent Application No. 101 31 931.2. Due to an apparent printing error, U.S. Patent Publication No. 2003/0066961 A1 refers to "JP" 101 31 931.2, whereas it should refer to "DE" 101 31 931.2.

EP 0 218 920 A2, listed on the attached PTO -1449 form, is a foreign language document. Both this document and U.S. Patent No. 4,740,704 (also listed on the PTO-1449 form) reflect a claim for foreign priority to German Patent Application No. 3532699.

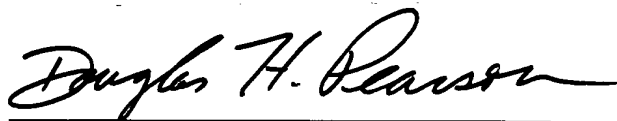
DE 100 44 199 A1, listed on the attached PTO-1449 form, is a foreign language document. Both this document and U.S. Patent Publication No. 2002/0084422 A1 (also listed on the PTO-1449 form) reflect a claim for foreign priority to German Patent Application No. 100 44 199.8.

Respectfully submitted,

BURNS, DOANE, SWECKER & MATHIS, L.L.P.

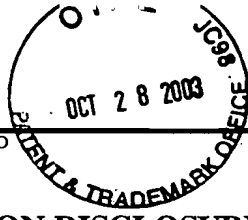
Date: October 28, 2003

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Substitute for forms 1449A/PTO & 1449B/PTO

**FIRST INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

ATTORNEY'S DKT No.

007413-056

APPLICATION No.

10/614,825

APPLICANT

Oliver KIENZLE et al.

FILING DATE

July 9, 2003

GROUP

Unassigned

U.S. PATENT DOCUMENTS

Examiner Initials	Document Number	Kind Code (if known)	Name of Patentee or Applicant of Cited Document	Issue/Publication Date (MM-DD-YYYY)
	2002/0084422	A1	Kienzle et al.	07-04-2002
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	4,376,249		Pfeiffer et al.	03-08-1983
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	WO 01/88514	A1	PCT International Publication	11-22-2001		
	WO 00/72355	A1	PCT International Publication	11-30-2000		
	WO 99/23684	A1	PCT International Publication	05-14-1999		
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	0 218 920	A2	Europe	04-22-1987		X
	100 44 199	A1	Germany	06-06-2002		X

NON PATENT LITERATURE DOCUMENTS

Examiner Initials	Include name of author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.
	Hansheng GUO et al., "Charging Phenomena and Charge Compensation in AES on Metal Oxides and Silica," SURFACE AND INTERFACE ANALYSIS, Vol. 25, pp. 390-396 (1997), John Wiley & Sons, Ltd.
	Miyako MATSUI et al., "Advanced inspection technique for deep-sub-micron and high-aspect-ratio contact holes," PROCEEDINGS OF SPIE, Vol. 4689, pp. 584-591 (2002), The International Society for Optical Engineering (SPIE).
	Eiichi GOTO et al., "MOL (moving objective lens) Formulation of defective aberration free system," OPTIC, Vol. 48, No. 3, pp. 255-270 (1977), Wissenschaftliche Verlagsgesellschaft mbH, Stuttgart, Germany.

Examiner
Signature

Date

Considered

EXAMINER: Initial if reference considered, whether or not citation is in conformance with M.P.E.P. § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. SEND TO: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.